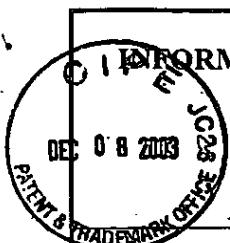


INFORMATION DISCLOSURE STATEMENT PTO-1449 <small>APR 26 2004</small> <small>SEARCHED INDEXED MAILED</small>		ATTY. DOCKET NO. 07783.0006.CPUS00		SERIAL NO. 09/784,972		
		APPLICANTS: Mary Chan-Park				
		FILING DATE: 2/15/2001		GROUP: 1756		
		U.S. PATENT DOCUMENTS				
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
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MD	4,655,897	04/07/1987	Disanto et al.	359	296	
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MD	6,652,075	Nov 2003	Jacobson	347	55	
MD	2001/0009352	07/26/2001	Moore	313	582	
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EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY (Inventor)	CLASS	SUBCLASS	TRANSLATION
						YES
MD	JP 59-034518	Feb 1984	Japan (English abstract included)			
MD	JP 62-099727	May 1987	Japan (English abstract included)			
MD	JP 62-203123	Sep 1987	Japan (English abstract included)			
MD	JP 01-300232	Dec 1989	Japan (English abstract included)			
MD	JP 02-223936	Sep 1990	Japan (English abstract included)			
MD	JP 04-113386	Apr 1992	Japan (English abstract included)			
MD	JP 09-160052	Jun 1997	Japan (English abstract included)			
MD	WO 97/04398	Pub Date 02/06/1997	PCT (Jacobson)			

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			26822-0006	09/784,972		
			APPLICANT: Mary Chan-Park, et al.			
			FILING DATE: 2/15/01	GROUP: 1756		
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EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
DD	*2002/0196525	12/26/2002	Chen et al.	291	RECEIVED 296	
DD	*2002/0018043	02/14/2002	Nakanishi	345	107	DEC 16 2003
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EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY (Inventor)	CLASS	SUBCLASS	TRANSLATION
						YES
DD	*2,340,683	Nat'l Entry Dt 2/14/2001	Canada (Schmidt, F. G.)			<input checked="" type="checkbox"/> <input type="checkbox"/>
DD	*EP 1195603	Pub Date 04/10/2002	Europe (Kawai)			<input type="checkbox"/> <input type="checkbox"/>
DD	*199 27 359.6	Pub. Date 12/21/00	Germany (Schmidt, F. G.)			<input type="checkbox"/> <input checked="" type="checkbox"/>
DD	*JP 2001 056653	Pub Date 02/27/2001	Japan (Hayakawa) (English abstract included)			<input type="checkbox"/> <input checked="" type="checkbox"/>
DD	*JP 02284126	Pub Date 11/21/1990	Japan (Oshiro) (English abstract included)			<input type="checkbox"/> <input checked="" type="checkbox"/>
DD	*WO 00/77571	Pub Date 12/21/00	PCT (Schmidt, F. G.)			<input type="checkbox"/> <input checked="" type="checkbox"/>
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DD	*Bryning et al., "Reverse-Emulsion Electrophoretic Display (REED)" <i>SID 98 Digest</i> 1018-1021 (1998)					
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DD	*Kishi, E et al, "5.1 Development of In-Plane EPD", Canon Research Center, <i>SID Digest</i> p. 24-27 (2000)					
DD	Danthu Chan-Park					
EXAMINER	DATE CONSIDERED 06/02/2004					

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ See English counterparts US Patent No. 6,512,626 or Canadian Patent Application No. 2,340,683. Applicant would be happy to obtain a direct translation of the document if desired.

**INFORMATION DISCLOSURE
STATEMENT**

PTO-1449

ATTY. DOCKET NO.

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APPLICANTS: Mary Chan-Park, et al.

FILING DATE: 2/15/01

GROUP: 1756

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
			RECEIVED			
			DEC 16 2003			
			TC 1700			

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EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY (Inventor)	CLASS	SUBCLASS	TRANSLATION	
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						<input type="checkbox"/>	<input type="checkbox"/>
						<input type="checkbox"/>	<input checked="" type="checkbox"/>

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ND	*Matsuda Y. "Newly designed, high resolution, active matrix addressing in plane EPD" <i>IDW 02 EP2-3</i> 1341-1344 (2002)
ND	*Ota et al. "Developments in Electrophoretic Displays" <i>Proc. of SID 18:243-254</i> (1977)
ND	*Swanson et al., "High Performance Electrophoretic Displays" <i>SID 00 Digest 29-31</i> (2000)

EXAMINER *D. brodthauer, Devs* DATE CONSIDERED *06/02/2004*

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.